

Accepted Manuscript

Title: Infrared-Spectroscopic Single-Shot Laser Mapping Ellipsometry: Proof of Concept for Fast Investigations of Structured Surfaces and Interactions in Organic Thin Films

Author: Andreas Furchner Christoph Kratz Dimitra Gkogkou
Helge Ketelsen Karsten Hinrichs



PII: S0169-4332(16)31796-2
DOI: <http://dx.doi.org/doi:10.1016/j.apsusc.2016.08.140>
Reference: APSUSC 33889

To appear in: *APSUSC*

Received date: 31-7-2016
Revised date: 24-8-2016
Accepted date: 26-8-2016

Please cite this article as: Andreas Furchner, Christoph Kratz, Dimitra Gkogkou, Helge Ketelsen, Karsten Hinrichs, Infrared-Spectroscopic Single-Shot Laser Mapping Ellipsometry: Proof of Concept for Fast Investigations of Structured Surfaces and Interactions in Organic Thin Films, *Applied Surface Science* (2016), <http://dx.doi.org/10.1016/j.apsusc.2016.08.140>

This is a PDF file of an unedited manuscript that has been accepted for publication. As a service to our customers we are providing this early version of the manuscript. The manuscript will undergo copyediting, typesetting, and review of the resulting proof before it is published in its final form. Please note that during the production process errors may be discovered which could affect the content, and all legal disclaimers that apply to the journal pertain.

1. An IR-spectroscopic mapping ellipsometer is developed based on a single-shot concept.
2. The ellipsometer is coupled to a broadband quantum cascade laser (1800–1540 cm⁻¹).
3. Unprecedented time resolutions of 60 ms are reached.
4. Mapping and spectroscopic features are applied for thin-film characterization.

Accepted Manuscript

Download English Version:

<https://daneshyari.com/en/article/5347719>

Download Persian Version:

<https://daneshyari.com/article/5347719>

[Daneshyari.com](https://daneshyari.com)